

Description

The SI7155DP-T1-GE3 uses advanced trench technology to provide excellent R_{DS(ON)}, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -40V$ $I_{D} = -100A$

 $R_{DS(ON)} < 4.1 \text{ m}\Omega \text{ V}_{GS}=-10 \text{V}$

Application

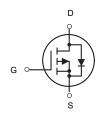
Battery protection

Load switch

Uninterruptible power supply

D D D S S S S S Pin 1

DFN5X6-8L



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)	
SI7155DP-T1-GE3	DFN5X6-8L	HXY MOSFET	5000	

Absolute Maximum Ratings (T_C=25°C unless otherwise noted)

Symbol	Parameter	ameter Rating		
Vos	Drain-Source Voltage -40		V	
Vgs	Gate-Source Voltage	±20	V	
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V	-100	А	
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V	-70	А	
Ідм	Pulsed Drain Current ² -400		А	
EAS	Single Pulse Avalanche Energy ³	1225	mJ	
P _D @T _C =25°C	Total Power Dissipation ⁴	200	W	
Тѕтс	Tstg Storage Temperature Range		°C	
TJ	Operating Junction Temperature Range -55 to 150		°C	
Rejc	Thermal Resistance,Junction-to-Case	0.95	°C/W	



Electrical Characteristics (T_J = 25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-40			V
$\triangleBV_{DSS}/\triangleT_J$	BV _{DSS} Temperature Coefficient	Reference to 250 , I _D =-1mA				V/°C
D	Static Drain-Source On-Resistance ²	V _{GS} =-10V , I _D =-13A		3.1	4.1	mO
R _{DS(ON)}		V _{GS} =-4.5V , I _D =-13A		4.4	5.4	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250uA	-1.2		-2.5	V
$\Delta V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	VGS-VDS , ID250UA				mV/°C
	Drain Source Leakage Current	V _{DS} =-40V , V _{GS} =0V , T _J =25°C			-1	uA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =-40V , V _{GS} =0V , T _J =55°C			-100	
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±20V , V _{DS} =0V			±100	nA
gfs	Forward Transconductance	V _{DS} =-10V , I _D =-13A		51		S
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.7		Ω
Qg	Total Gate Charge			195		
Q _{gs}	Gate-Source Charge	V _{DS} =-20V , V _{GS} =-10V , I _D =-13A		24.1		nC
Q _{gd}	Gate-Drain Charge			39.9		
T _{d(on)}	Turn-On Delay Time			19.6		
T _r	Rise Time	V _{DD} =-20V , V _{GS} =-10V ,		3.6		no
T _{d(off)}	Turn-Off Delay Time	R _G =3.3Ω		22.8		ns
T _f	Fall Time			38		
C _{iss}	Input Capacitance			10733		
Coss	Output Capacitance	V _{DS} =-20V , V _{GS} =0V , f=1MHz		770		pF
C _{rss}	Reverse Transfer Capacitance			697		

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,4}	V _G =V _D =0V , Force Current			-100	Α
VsD	Diode Forward Voltage ²	V _{GS} =0V , I _S =-13A , T _J =25°C			-1.2	V
t _{rr}	Reverse Recovery Time	IF=-13A , di/dt=100A/µs ,		51.1		nS
Qrr	Reverse Recovery Charge	TJ=25°C		125.2		nC

FÈThe Ádata Á ested Á by Ásurface Á nounted Áon Ás Ál Ánch^{2 Á}FR-4 Á soard Á with Á2OZ Á copper.

ĠŤheÁlataÁlestedÁbyÁpulsedÁÁpulseÁwidthÁg 300usÁÁlutyÁsycleÁg 2% HŤhe EAS data shows Max. rating . The test condition is TJ=25 C,VDD=-40V,VG=-10V, Rg=25Ω, L=0.5mH.

dissipation.



Typical Performance Characteristics

Figure 1. Output Characteristics

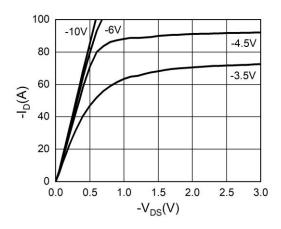


Figure 3. Power Dissipation

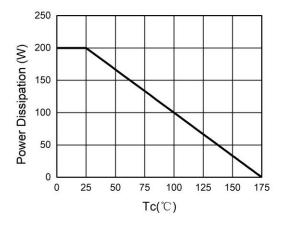


Figure 5. BV_{DSS} vs Junction Temperature

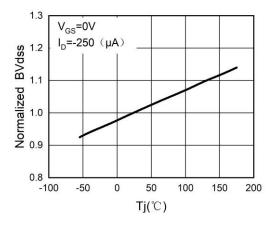


Figure 2. Transfer Characteristics

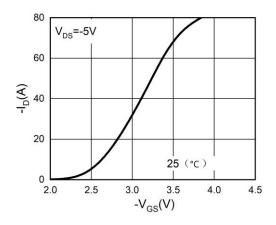


Figure 4. Drain Current

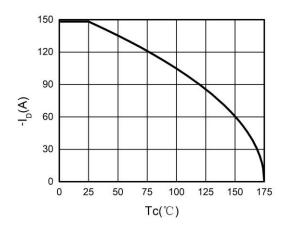


Figure 6. R_{DS(ON)} vs Junction Temperature

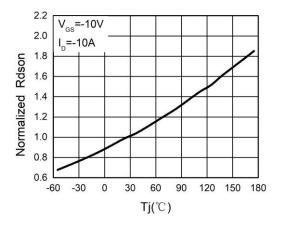


Figure 7. Gate Charge Waveforms

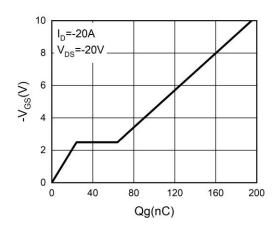


Figure 8. Capacitance

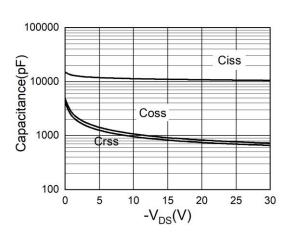


Figure 9. Body-Diode Characteristics

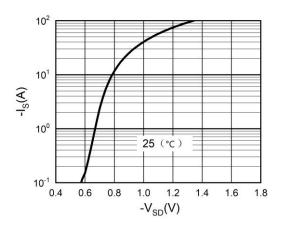
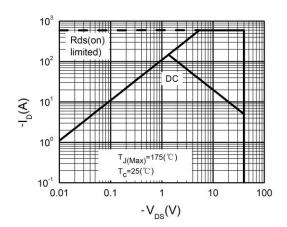
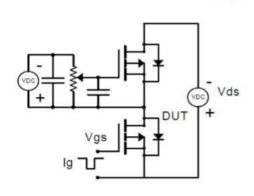


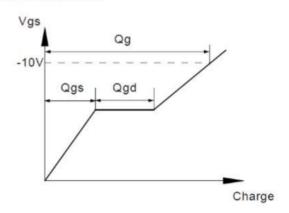
Figure 10. Maximum Safe Operating Area



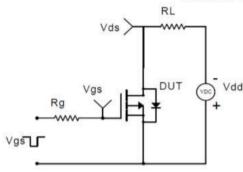
Test Circuit

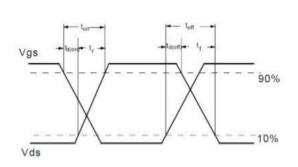
Gate Charge Test Circuit & Waveform



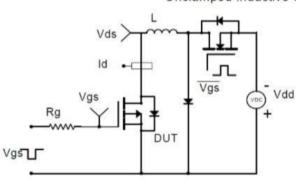


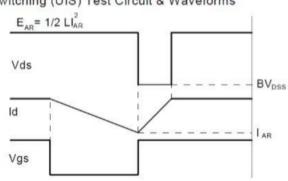
Resistive Switching Test Circuit & Waveforms



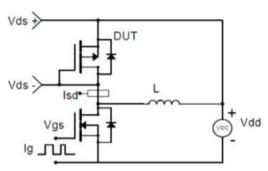


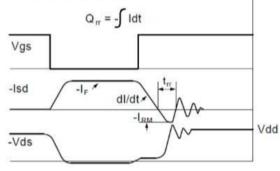
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





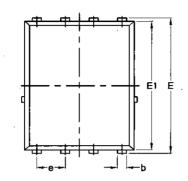
Diode Recovery Test Circuit & Waveforms

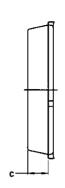


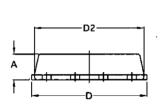


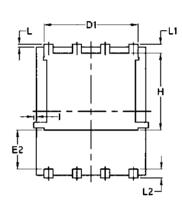


DFN5X6-8L Package Information









Symbol	Common	Common					
	mm	mm					
	Mim	Max	Min	Max			
A	1.03	1.17	0.0406	0.0461			
b	0.34	0.48	0.0134	0.0189			
С	0.824	0.0970	0.0324	0.082			
D	4.80	5.40	0.1890	0.2126			
D1	4.11	4.31	0.1618	0.1697			
D2	4.80	5.00	0.1890	0.1969			
E	5.95	6.15	0.2343	0.2421			
E1	5.65	5.85	0.2224	0.2303			
E2	1.60	/	0.0630	/			
е	1.27 BSC		0.05 BSC				
L	0.05	0.25	0.0020	0.0098			
L1	0.38	0.50	0.0150	0.0197			
L2	0.38	0.50	0.0150	0.0197			
Н	3.30	3.50	0.1299	0.1378			
I	1	0.18	1	0.0070			



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